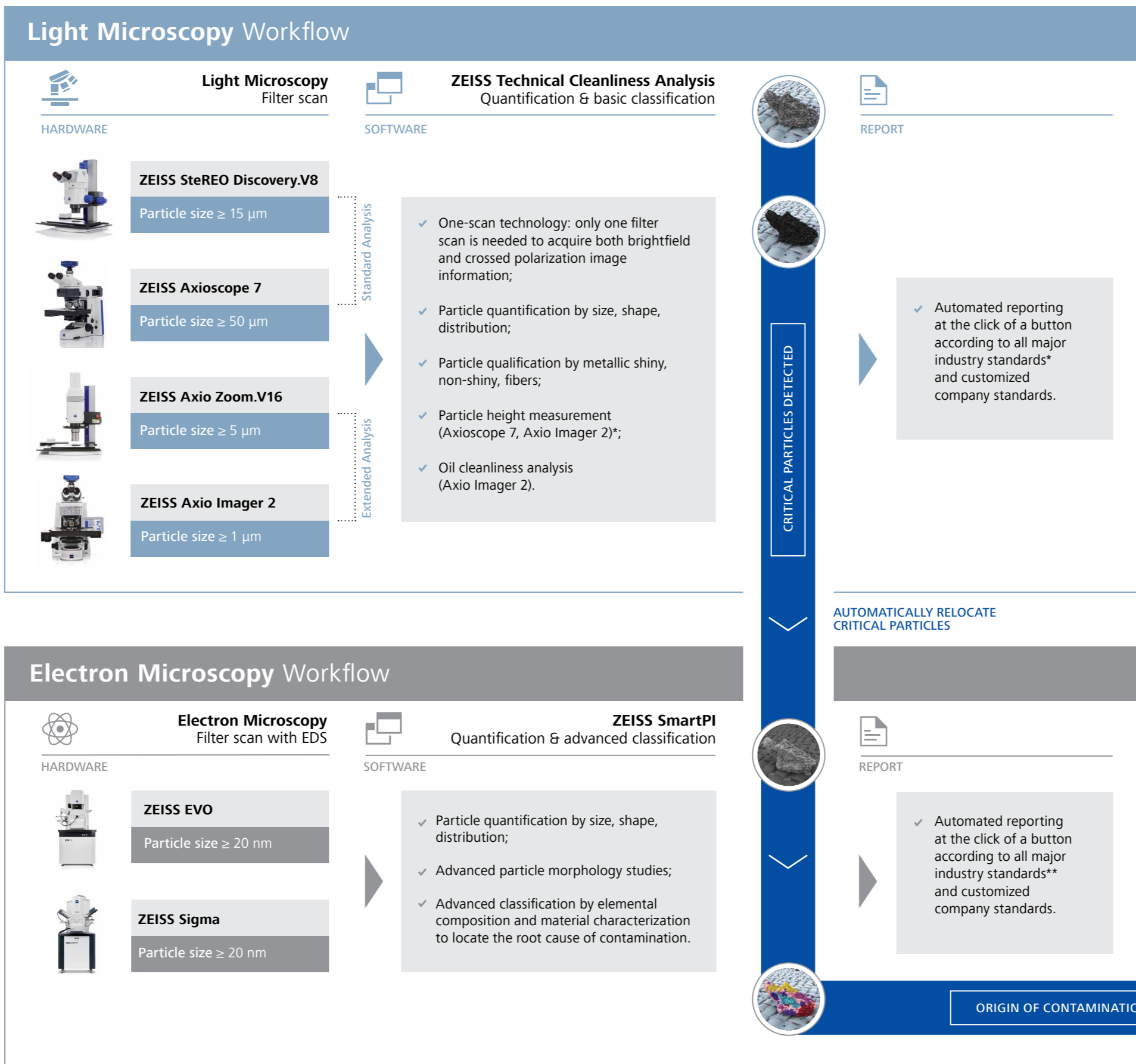


ZEISS Correlative Particle Analysis Workflow

Identify the root cause, make the right decision faster.



ZEISS CAPA
Correlative Automated
Particle Analysis

Correlated analysis across Light and Electron microscopy in a seamless integrated workflow

- Automatic integrated LM / EM reporting;
- Pinpoint sources of contamination;
- Make informed decisions faster;
- Continually improve production quality.

UP TO 10X FASTER RESULTS VERSUS CONSECUTIVE INDIVIDUAL ANALYSIS

** Supported industry standards: VDA 19.1, ISO 16232, ISO 4406, ISO 4007, DIN 51455*, SAE AS 4059, VDI 2083, NAS 1638
* Available as of 2021